S	earch	arch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/714,801	CHOI ET AL.
Examiner	Art Unit
David E. Graybill	2822

SEARCHED		
Subclass	Date	Examiner
-		
	Subclass	Subclass Date

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		-	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) - Printout	3/4/2007	DG
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